

SCANWORKS® PCI-110 LVDS CONTROLLER CARD

PCI-110 LVDS PRODUCT OVERVIEW

The PCI-110 LVDS controller (Low-voltage differential signaling) supports the application of structural tests, programming operations and tests created with ScanWorks® Boundary-Scan Test (BST). Examples of structural tests (shorts and opens testing) are scan path verification, interconnect tests, and memory access tests. Programming operations include flash programming, PLD configuration, and programming I2C or SPI devices. Using the PCI-110 LVDS enables the application of all these scan operations with one boundary-scan controller and one connection to the UUT (unit under test).

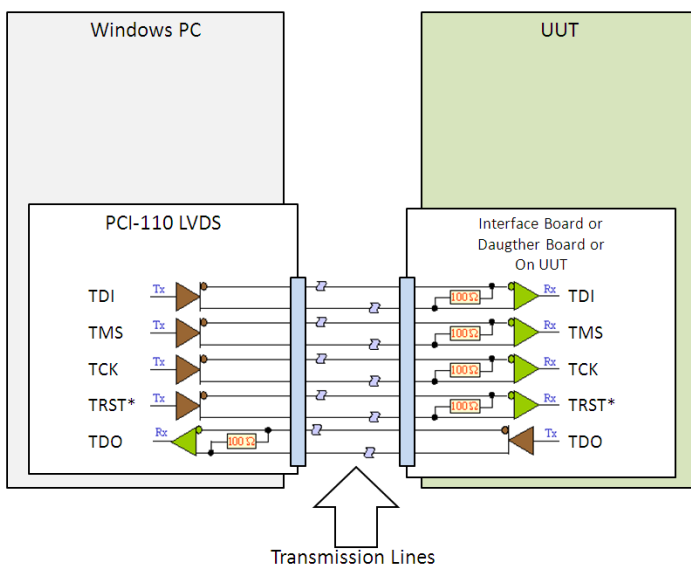
Its special TAP interface (TDI, TDO, TMS, TCK, and TRST) is based on LVDS signals and built for UUT's,



or interface boards, with a differential TAP interface. Figure 1 shows an example connection to a UUT. The controller is installed in a PCI slot in the PC on which ScanWorks is running. The PCI-110 LVDS connects directly to the UUT. LVDS allows tests to be run at higher speed and over longer distances. The PCI-110 LVDS provides a sustained data throughput at high TCK frequencies allowing very fast structural test and in-system configuration application times.

PROGRAMMABLE CLOCK

The differential TCK signals provided by the PCI-110 LVDS controller are programmable from 160kHz to 50MHz. The TCK frequency is controllable from the ScanWorks hardware setup menu, or from FREQUENCY statements in SVF and STAPL files. The controller always operates in a “hybrid TCK mode”, which is a combination of “free-running” and “gated” mode allowing test of some non-compliant IEEE 1149.1 devices.





VOLTAGES

The controller supports LVDS signal levels.

PHYSICAL FEATURES

The controller is built to commercial environmental standards for the U.S. and Europe.

PC REQUIREMENTS

Only one controller is supported per PC. The PC must have a full height PCI slot available. The Windows XP and Window 7 32-bit operating systems are supported.

FULL LIFE-CYCLE SUPPORT

During the design/debug or the field service stage of your product's life cycle, the PCI-110 LVDS controller card provides you with a robust and flexible interface from your host test platform to your board. It is fast enough to provide maximum scan throughput to all but the most highly optimized scan paths, yet inexpensive enough to be used in high volume production. By using the same controller in design/debug test development and manufacturing, you eliminate any question of compatibility.

ASSET CONTACTS:

Please contact your ScanWorks sales representative for more information on specific features or for a personalized analysis of how Dispatcher can solve your high-volume manufacturing problems.

<http://www.asset-intertech.com/contact.html>

ASSET InterTech, Inc.
2201 N. Central Expy., Ste 105
Richardson, TX 75080
+1 888 694-62500 or +1 972 437-2800
<http://www.asset-intertech.com>